## Notice of References Cited Application/Control No. 10/788,925 Examiner Michael J. Zanelli Applicant(s)/Patent Under Reexamination MIWA, YOHEI Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,543,802	08-1996	Villevieille et al.	342/357.06
*	В	US-6,459,987	10-2002	Krull et al.	701/213
*	С	US-6,115,655	09-2000	Keith et al.	701/35
*	D	US-6,321,158	11-2001	DeLorme et al.	701/201
*	Е	US-6,199,010	03-2001	Richton, Robert Ellis	701/206
*	F	US-2002/0107635	08-2002	Katayama et al.	701/207
*	G	US-5,546,092	08-1996	Kurokawa et al.	342/357.06
	Н	US-6,047,235	04-2000	Hiyokawa et al.	701/201
	1	US-4,563,685	01-1986	Matsumoto et al.	340/995.21
	J	US-6,765,528	07-2004	Tranchina et al.	342/357.1
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	Φ					
	α					
	R					
	s					
	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	х	

<sup>\*</sup>A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.